

Fig. 2. The co- and cross-line reflection and transmission coefficients given by the explicit solutions (49) and (50) for two coupled identical exponential lines with the parameters $C_0 = C_{10} = C_{00}$, $C_{m0} = 0.5C_{00}$, $L_0 = 3L_{00}$, $L_{10} = 0.8L_{00}$, $L_{m0} = 2L_{00}$ and the frequency $\omega = 0.1/l\sqrt{L_{00}C_{00}}$. The marks in the figure are the corresponding co- and cross-line scattering coefficients obtained by solving numerically the ODE's for the reflection-coefficient matrix and the Green's functions.

V. CONCLUSION

The exact and explicit expressions for the co- and cross-line reflection and transmission coefficients for two coupled identical exponential lines have been derived. The explicit expressions have been validated by a numerical solution based on the wave-splitting technique.

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Operation of New Type Field Displacement Isolator in Ridged Waveguide

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Abstract—A new type ridged-waveguide field-displacement isolator is analyzed in this paper. Experimental results have been obtained for the isolation, insert loss, and voltage standing wave ratio (VSWR) in C- and X-band. The isolation and bandwidth are found to increase obviously.

Index Terms—Isolator, ridged waveguide.

I. INTRODUCTION

In 1960, Chen [1] proposed the experimental results of resonating isolator and field displacement isolator in a single ridged waveguide. He got useful results of the resonating isolator. As to the field displacement isolator, his experiments were failures. He found "the forward loss of the field displacement isolator in single ridged waveguide became nearly identical with the reverse loss, nonreciprocal effect was not distinct. Take out the resistance sheet, nonreciprocal effect couldn't be improved..." Based on the study of [2]–[5], the authors think that Chen's failure is due to the asymmetry of the single ridge positioned in the waveguide, which caused asymmetrical field distribution, and to the spacing of the ridge from the ferrite, which was so far that the circular polarization field besides the ridge could not interfere with the magnetized ferrite. According to previous analysis, the authors propose a new type field displacement isolator in symmetrical ridged waveguide. The experimental work has shown

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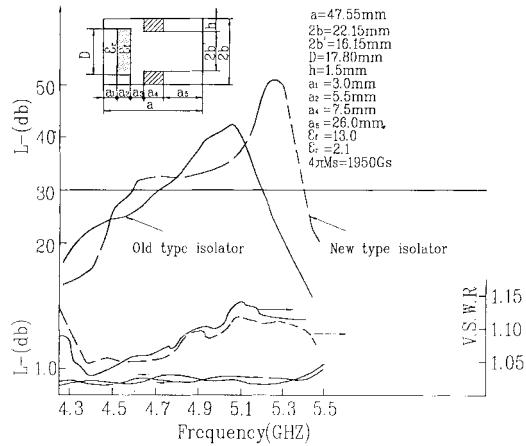


Fig. 1. Measured operation of new type field displacement isolator in ridged waveguide and old type isolator in rectangular waveguide in *C*-band.

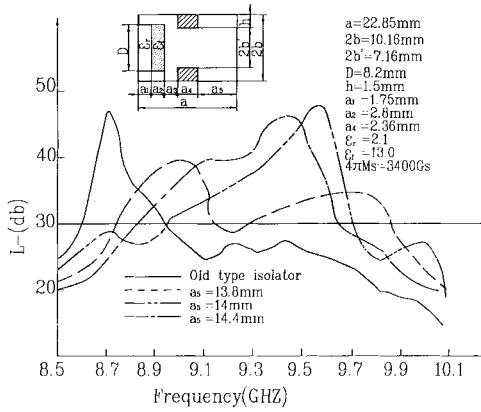


Fig. 2. Measured operation of new type field displacement isolator in ridged waveguide and old type isolator in rectangular waveguide in *X*-band.

that isolation and the bandwidth of the new type device have been improved.

II. EXPERIMENTAL RESULTS

For the sake of the study, the authors use the ridged waveguide to replace the rectangular one, and do some experiments as following. In *C*-band, the length of the ferrite bar is 118.5 mm, the experimental results are shown in Fig. 1, where it can be seen that: 1) when the isolation L_- is 30 dB, the bandwidth of the new type device is 14.73%, while that of the old type device is 9.7%; 2) the maximum isolation of the new type device is 7 ~ 8 dB larger than that of the old type device; and 3) the forward loss L_+ of the new type device is slightly larger than that of the old type device. In *X*-band, the length of the ferrite bar is 37.5 mm, with the experimental results shown in Fig. 2. One can see that the isolation of the new type device is larger than that of the old type device. The experimental results have also shown that the forward loss of the new type device is larger slightly than that of the old type device.

III. THEORETICAL CONSIDERATION

Since the ferrite and dielectric slabs loaded into the field displacement isolator are not "full height," it would be very difficult to get a closed form solution. In order to verify the isolation increase of the new type device, the authors draw in the analytical model [7] shown in Fig. 3, and use the transverse matrix method [3] to deduce the

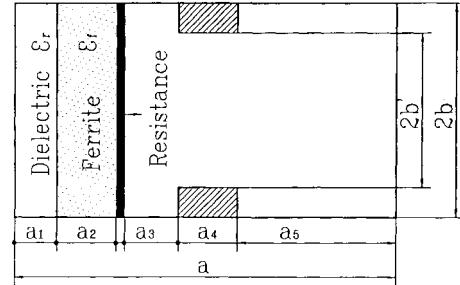


Fig. 3. Analytical model.

transcendental equation of the field displacement isolator in ridged waveguide as following:

$$\begin{aligned} j(A + B/Z)(tg\Phi + \xi tg\theta - vtg\theta tg\Phi) \\ - B(1 + v^2)tg\theta tg\Phi/\xi + B(1 + vtg\theta) = 0 \end{aligned} \quad (1)$$

where

$$\begin{aligned} A &= 1 + j2Y_1tg\Phi_1 - \left(\frac{b}{b'} + Y_1^2 \frac{b'}{b} \right) tg\Phi_1 tg\Phi_2 + jY_1 \frac{b'}{b} tg\Phi_2 \\ &\quad - \frac{b'}{b} tg\Phi_2 tg\varphi_3 - jY_1 \frac{b'}{b} tg\Phi_1 tg\Phi_2 tg\Phi_3 - tg\Phi_1 tg\Phi_3 \\ B &= jtg\Phi_1 + j \frac{b'}{b} tg\Phi_2 + jtg\Phi_3 - 2Y_1tg\Phi_1 tg\Phi_3 \\ &\quad - j \left(\frac{b}{b'} + Y_1^2 \frac{b'}{b} \right) \cdot tg\Phi_1 tg\Phi_2 tg\Phi_3 \\ &\quad - Y_1 \frac{b'}{b} tg\Phi_2 tg\Phi_3 - \frac{b'}{b} Y_1 tg\Phi_1 tg\Phi_2 \\ \Phi_1 &= k_a a_5, \quad \Phi_2 = k_a a_4, \quad \Phi_3 = k_a a_3, \\ \theta &= k_m a_2, \quad \Phi = k_c a_1 \\ k_a &= \sqrt{\frac{\omega^2}{C^2} + \Gamma^2} \\ k_m &= \sqrt{\frac{\omega^2}{C^2} \epsilon_f \mu_e + \Gamma^2} \\ k_c &= \sqrt{\frac{\omega^2}{C^2} \epsilon_r + \Gamma^2} \\ v &= - \frac{jk\Gamma}{\mu k_m} \\ \xi &= \frac{k_a}{k_m} \frac{\mu^2 - k^2}{\mu} \\ Z &= \frac{R_s k_a}{\omega \mu_0} \\ Y_1 &= j2b\omega C_d \\ C &= \text{the light speed} \\ C_d &= \text{see [8], references herein.} \end{aligned}$$

Calculation parameters are given in the experimental results. The frequency range is from 8.0 to 11.0 GHz. The theoretical results are shown in the plots of Fig. 4, where it can be seen that the isolation of the new type device is about 3 dB larger than that of the old type one, which is roughly consistent with the experimental results shown in Fig. 2. The calculation has also shown that the isolation of the new type device reaches its maximum value at $a_4 = 2.5$ mm, which agrees with the experimental results shown in Fig. 2.

IV. CONCLUSION

In this paper, how to improve the isolation and bandwidth of the field displacement isolator in rectangular waveguide has been

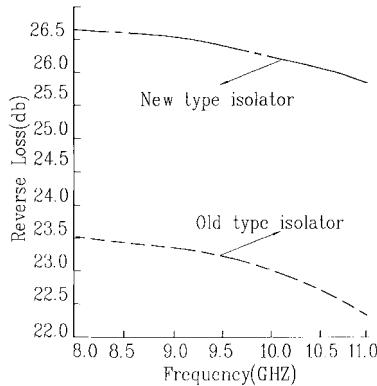


Fig. 4. Calculated reverse loss with frequency for new type isolator and old type isolator in X-band.

considered. The propagation constant transcendental equation has been deduced. By using appropriate ridged waveguide instead of rectangular one, it is possible to increase the isolation and bandwidth of the field displacement isolator, thus making it easier to get a good match. However, the forward insert loss of the new type device is slightly larger than that of the old type devise, and how to reduce the forward loss is of further work. The authors believe that this paper has resulted in a sufficient amount of knowledge regarding the device and provides a quantitative guide to the design of microwave devices.

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An Accurately Scaled Small-Signal Model for Interdigitated Power P-HEMT up to 50 GHz

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Abstract—In this paper, the authors report an approach for constructing scalable small-signal models for interdigitated power pseudomorphic high-electron-mobility transistors (P-HEMT's). By using cold-FET and Yang-Long measurement, as well as direct extraction procedures, scaling rules for extrinsic components were established that allow accurate models over a broad frequency range. These models have been used to design ultrawide-band monolithic microwave integrated circuits (MMIC's) up to 50 GHz.

I. INTRODUCTION

Small-signal equivalent models are used frequently in the design of power amplifier (PA), low-noise amplifier (LNA), and other subsystem components. A small-signal model which provides good accuracy and can be scaled based on layout structures, as well as gatewidth, is useful when various FET sizes are needed or models are simply not available. Unlike the small-signal model that is determined by computer optimization, a physically related one can be useful in the characterization of fabrication processes and for scaling purposes. In addition to providing an equivalent circuit to predict MMIC electrical performance, a scalable modeling approach is also useful in determining the noise parameters [1]-[2]. In this paper, an approach to constructing a scalable small-signal model from cold-FET, Yang-Long measurement, and RF data for an interdigitated power pseudomorphic high-electron-mobility transistor (P-HEMT) is presented. Approaches for selecting the parameters from data sets are discussed. The scaling factors for extrinsic components (R_g , R_d , R_s , L_g , L_d , L_s , C_{pg} , and C_{pd}) are given after careful examination of the measured data. The S -parameter comparison between scaled models and measured data are shown up to 50 GHz.

II. POWER P-HEMT DEVICE STRUCTURE AND EQUIVALENT CIRCUIT

The pseudomorphic InGaAs/AlGaAs HEMT device structure was used in this paper. The device profile is a double-heterojunction HEMT grown by molecular beam epitaxy (MBE). Silicon planar doping is employed on both heterojunctions to provide carriers to the InGaAs channel. The AlGaAs layer with the planar doping was left undoped and the Schottky gate was recessed to this region. Ohmic contacts were formed with an optimized rapid thermal annealing (RTA) AuGeNi-based metallization scheme. Device isolation was achieved by boron ion implantation. The devices were passivated with SiN film deposited by plasma-enhanced chemical-vapor deposition (PECVD). Due to the use of undoped AlGaAs, the gate-drain breakdown voltage (defined at 1 mA/mm) is greater than 12 V.

Fig. 1 shows the chosen equivalent circuit topology for the interdigitated power P-HEMT. The P-HEMT layout in wafer process control monitored (PCM) sites is shown in Fig. 2. The S -parameters of five different FET's, 100 μ m (25 \times 4, two gate feeds), 198 μ m (33 \times 6, three gate feeds), 300 μ m (30 \times 10, five gate feeds), 396 μ m (33 \times 12, six gate feeds), and 600 μ m (50 \times 12, six gate feeds) are measured and their small-signal models are extracted with methods discussed below.

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